Search Notes

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/728,529	FUNAKI, TOMOYUKI	
Examiner	Art Unit	
Jinhee J. Lee	2174	

	SEARCHED				
Class	Subclass	Date	Examiner		
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ראו	INTERFERENCE SEARCHED				
Class	Subclass	Date	Examiner.		
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
	DATE	EXMR		
East text search attached	1/21/2007	LEE		
V. Tran 101 and product by process	7/6/2007	LEE		
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